









# RF Exposure Evaluation Declaration

Product Name: EZ-BLE PRoC XR Module

Model No. : CYBLE-212006-01;

CYBLE-202007-01

FCC ID : WAP2006

Applicant : Cypress Semiconductor

Address : 198 Champion Ct, San Jose, California 95134 United

**States** 

Date of Receipt: Jun. 28, 2016

Issued Date : Aug. 24, 2016

Report No. : 1662128R-RF-US-P20V02

Report Version: V1.0

The test results relate only to the samples tested.

The test results shown in the test report are traceable to the national/international standard through the calibration of the equipment and evaluated measurement uncertainty herein.

This report must not be used to claim product endorsement by TAF any agency of the government.

The test report shall not be reproduced without the written approval of QuieTek Corporation.



## **Test Report Certification**

Issued Date : Aug. 24, 2016

Report No.: 1662128R-RF-US-P20V02



Product Name : EZ-BLE PRoC XR Module

Applicant : Cypress Semiconductor

Address : 198 Champion Ct, San Jose, California 95134 United

States

Manufacturer : Wujiang Sigmatron Electronics Co., Ltd

Address : 386 Huahong Rd, Wujiang, Suzhou, Jiangsu, China

Model No. : CYBLE-212006-01; CYBLE-202007-01

FCC ID : WAP2006

EUT Voltage : DC 2.0 ~ 3.6V

Applicable Standard : KDB 447498 D01v06

Test Result : Complied

Performed Location : Quietek Corporation - Suzhou EMC Laboratory

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215006, Jiangsu, China

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Reviewed By :

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Approved By : Harry Their

(Engineering Manager : Harry Zhao )



## **Laboratory Information**

We, **QuieTek Corporation**, are an independent EMC and safety consultancy that was established the whole facility in our laboratories. The test facility has been accredited/accepted(audited or listed) by the following related bodies in compliance with ISO 17025, EN 45001 and specified testing scope:

Taiwan R.O.C. : BSMI, NCC, TAF

USA : FCC
Japan : VCCI
China : CNAS

The related certificate for our laboratories about the test site and management system can be downloaded from QuieTek Corporation's Web Site: <a href="http://www.quietek.com/english/about/certificates.aspx?bval=5">http://www.quietek.com/english/about/certificates.aspx?bval=5</a>
The address and introduction of QuieTek Corporation's laboratories can be founded in our Web site: <a href="http://www.quietek.com/index\_en.aspx">http://www.quietek.com/index\_en.aspx</a>

If you have any comments, Please don't hesitate to contact us. Our contact information is as below:

## **HsinChu Testing Laboratory:**

#### **LinKou Testing Laboratory:**

No.5-22, Ruishukeng, Linkou Dist., New Taipei City 24451, Taiwan, R.O.C.

## **Suzhou Testing Laboratory:**

No.99 Hongye Rd., Suzhou Industrial Park, Suzhou, 215006, Jiangsu, China



## 1. RF Exposure Evaluation

#### 1.1. Limits

According to KDB 447498 D01 General RF Exposure Guidance v06

#### 4.3.1 Standalone SAR test exclusion considerations

1) The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)]  $\cdot [\sqrt{f(GHz)}]$   $\leq 3.0$  for 1-g SAR and  $\leq 7.5$  for 10-g extremity SAR,where

- f(GHz) is the RF channel transmit frequency in GHz
- · Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison
- 3.0 and 7.5 are referred to as the numeric thresholds in the step 2 below

The test exclusions are applicable only when the minimum test separation distance is  $\leq$  50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is  $\leq$  5 mm, a distance of 5 mm according to 5) in section 4.1 is applied to determine SAR test exclusion.

- 2) At 100 MHz to 6 GHz and for test separation distances > 50 mm, the SAR test exclusion threshold is determined according to the following, and as illustrated in Appendix B:
- a) [Power allowed at numeric threshold for 50 mm in step 1) + (test separation distance 50 mm)·( f(MHz)/150)] mW, at 100 MHz to 1500 MHz
- b) [Power allowed at numeric threshold for 50 mm in step 1) + (test separation distance 50 mm)·10] mW at > 1500 MHz and  $\leq$  6 GHz
- 3) The 1-g and 10-g SAR test exclusion thresholds for below 100 MHz at test separation distances ≤ 50 mm are determined by:
- a) The power threshold at the corresponding test separation distance at 100 MHz in step 2) is multiplied by [1 + log(100/f(MHz))] for test separation distances > 50 mm and < 200 mm
- b) The power threshold determined by the equation in a) for 50 mm and 100 MHz is multiplied by  $\frac{1}{2}$  for test separation distances  $\leq$  50 mm
- c) SAR measurement procedures are not established below 100 MHz. When SAR test exclusion cannot be applied, a KDB inquiry is required to determine SAR evaluation requirements for any test results to be acceptable. Note: when the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.



## 1.2. Test Procedure

Software provided by client enabled the EUT to transmit and receive data at lowest, middle and highest channel individually.

## 1.3. Test Result of RF Exposure Evaluation

Product	:	EZ-BLE PRoC XR Module			
Test Item	:	RF Exposure Evaluation			
Test Site	:	AC-6			

## Antenna Gain:

Model No.	N/A	N/A							
Antenna manufacturer	N//A								
Antenna Delivery		1*TX+1*R	RX		2*TX+2*RX		] 3*TX+3*RX		
Antenna technology									
		MIMO		Basic					
				CDD					
				Beam-forming					
Antenna Type		External		Dipole					
		Internal		PIFA					
			$\boxtimes$	PCB					
				Ceramic Chip Antenna					
				Metal plate type F antenna					
Antenna Gain -0.5dBi									
Model No.	B484	B4844-01							
Antenna manufacturer	Ante	Antenova							
Antenna Delivery		1*TX+1*R	RX		2*TX+2*RX		] 3*TX+3*RX		
Antenna technology	$\boxtimes$	SISO							
		] мімо		Basic					
				CDD					
				Beam-forming					
Antenna Type		External	$\boxtimes$	Dipole	e				
		Internal		PIFA		_			
		Intornal							

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			Ceramic Chip Antenna
			Metal plate type F antenna
Antenna Gain	2.20	dBi	

Based on The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm and the formula below:

Estimated SAR=
$$\sqrt{f(GHz)} * \frac{\text{(Max Power of channel, mW)}}{\text{Min. Separation Distance, mm}}$$

Band	Exposure Condition	Pmax	Pmax	Distance	f(CU=)	calculation result	Stand-alone Test	SAR Test
		(dBm)	(mw)	(mm)	f(GHz)		exclusion	
		(abiii)	(11144)				threshold	
ВТ	Body	8.37	6.87	5	2.480	2.16	3.00	No

Conclusion: 2400MHz-2480MHz SAR was not required.

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